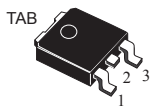
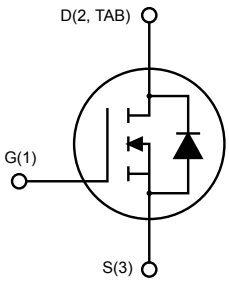
EN: This Datasheet/Document is presented by the manufacturer.

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N-channel 650 V, 0.230 Ω typ., 12 A MDmesh™ M5 Power MOSFET in a DPAK package



DPAK



AM01475v1_noZen

Features

Order codes	V_{DS} at $T_{jmax.}$	$R_{DS(on)}$ max.	I_D
STD16N65M5	710 V	0.279 Ω	12 A

- Extremely low $R_{DS(on)}$
- Low gate charge and input capacitance
- Excellent switching performance
- 100% avalanche tested

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET based on the MDmesh™ M5 innovative vertical process technology combined with the well-known PowerMESH™ horizontal layout. The resulting product offers extremely low on-resistance, making it particularly suitable for applications requiring high power and superior efficiency.

Product status link
STD16N65M5

Product summary	
Order code	STD16N65M5
Marking	16N65M5
Package	DPAK
Packing	Tape and reel

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	±25	V
I_D	Drain current (continuous) at T_C = 25 °C	12	A
I_D	Drain current (continuous) at T_C = 100 °C	7.3	A
I_{DM} (1)	Drain current (pulsed)	48	A
P_{TOT}	Total power dissipation at T_C = 25 °C	90	W
dv/dt (2)	Peak diode recovery voltage slope	15	V/ns
T_j	Operating junction temperature range	-55 to 150	°C
T_{stg}	Storage temperature range		

1. *Pulse width limited by safe operating area.*
2. *I_{SD} ≤ 12 A, di/dt ≤ 400 A/µs, V_{DD} = 400 V, $V_{DS(peak)}$ < $V_{(BR)DSS}$.*

Table 2. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj\text{-}case}$	Thermal resistance junction-case	1.38	°C/W
$R_{thj\text{-}pcb}$ (1)	Thermal resistance junction-pcb	50	°C/W

1. *When mounted on 1inch² FR-4 board, 2 oz Cu.*

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or not-repetitive (pulse width limited by T_j Max)	4	A
E_{AS}	Single pulse avalanche energy (starting T_j = 25 °C, I_D = I_{AR}, V_{DD} = 50 V)	200	mJ

2 Electrical characteristics

(T_{CASE} = 25 °C unless otherwise specified)

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	I_D = 1 mA, V_{GS} = 0 V	650			V
I_{DSS}	Zero gate voltage drain current	V_{GS} = 0 V, V_{DS} = 650 V,			1	µA
		V_{GS} = 0 V, V_{DS} = 650 V, T_C = 125 °C (1)			100	µA
I_{GSS}	Gate body leakage current	V_{DS} = 0 V, V_{GS} = ±25 V			100	nA
$V_{GS(th)}$	Gate threshold voltage	V_{DS} = V_{GS}, I_D = 250 µA	3	4	5	V
$R_{DS(on)}$	Static drain-source on resistance	V_{GS} = 10 V, I_D = 6 A		0.230	0.279	Ω

1. *Defined by design, not subject to production test.*

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	V_{DS} = 100 V, f = 1 MHz, V_{GS} = 0 V	-	1250	-	pF
C_{oss}	Output capacitance			30		
C_{rss}	Reverse transfer capacitance			3		
$C_{o(tr)}$ (1)	Equivalent capacitance time related	V_{DS} = 0 to 520 V, V_{GS} = 0 V	-	100	-	pF
$C_{o(er)}$ (2)	Equivalent capacitance energy related		-	30	-	pF
Rg	Gate input resistance	f = 1 MHz open drain	-	2	-	Ω
Q_g	Total gate charge	V_{DD} = 520 V, I_D = 12 A, V_{GS} = 0 to 10 V (see Figure 15. Test circuit for gate charge behavior)	-	31	-	nC
Q_{gs}	Gate-source charge			8		
Q_{gd}	Gate-drain charge			12		

1. *$C_{o(tr)}$ time related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}.*
2. *$C_{o(er)}$ energy related is defined as a constant equivalent capacitance giving the same stored energy as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}.*

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(v)}$	Voltage delay time	V_{DD} = 400 V, I_D = 8 A,	-	25	-	ns
$t_{r(v)}$	Voltage rise time	R_G = 4.7 Ω, V_{GS} = 10 V		7		
$t_{f(i)}$	Current fall time	(see Figure 16. Test circuit for inductive load switching and diode recovery times and Figure 19. Switching time waveform)		6		
$t_{c(off)}$	Crossing time			8		

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		12	A
I_{SDM} (1)	Source-drain current (pulsed)				48	
V_{SD} (2)	Forward on voltage	I_{SD} = 12 A, V_{GS} = 0 V	-		1.5	V
t_{rr}	Reverse recovery time	I_{SD} = 12 A, di/dt = 100 A/µs	-	300		ns
Q_{rr}	Reverse recovery charge	V_{DD} = 100 V (see Figure 16. Test circuit for inductive load switching and diode recovery times)		3.5		µC
I_{RRM}	Reverse recovery current			23		A
t_{rr}	Reverse recovery time	I_{SD} = 12 A, di/dt = 100 A/µs	-	350		ns
Q_{rr}	Reverse recovery charge	V_{DD} = 100 V (see Figure 16. Test circuit for inductive load switching and diode recovery times)		4		µC
I_{RRM}	Reverse recovery current			24		A

1. *Pulse width limited by safe operating area.*
2. *Pulsed: pulse duration = 300 µs, duty cycle 1.5%.*

2.1 Electrical characteristics curves

Figure 1. Safe operating area

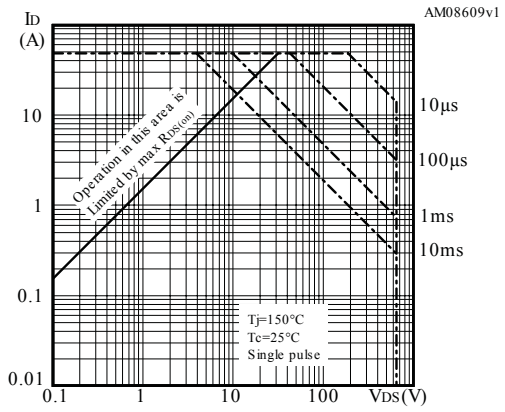


Figure 2. Thermal impedance

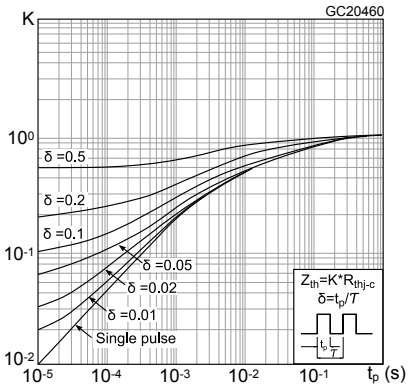


Figure 3. Output characterisics

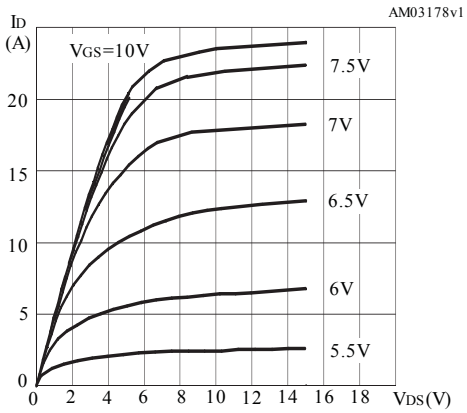


Figure 4. Transfer characteristics

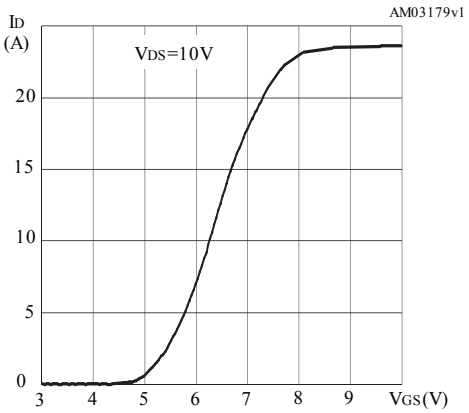


Figure 5. Normalized $V_{(BR)DSS}$ vs temperature

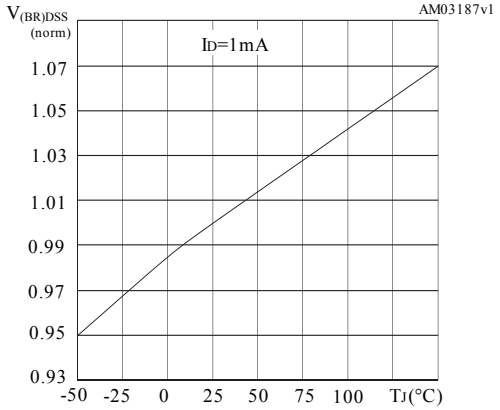


Figure 6. Static drain-source on resistance

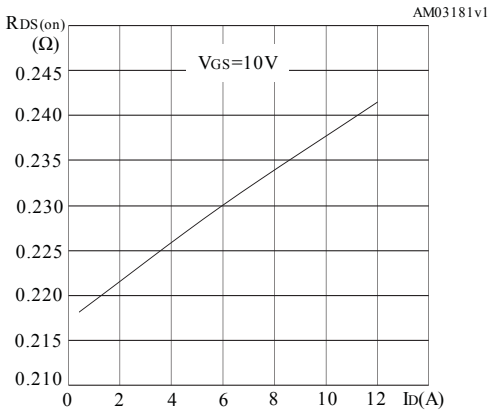


Figure 7. Output capacitance stored energy

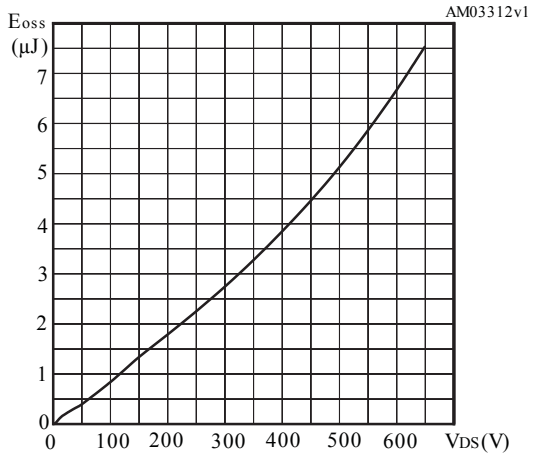


Figure 8. Capacitance variations

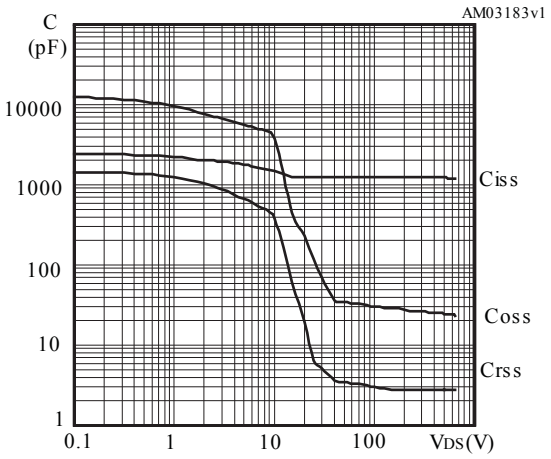


Figure 9. Gate charge vs gate-source voltage

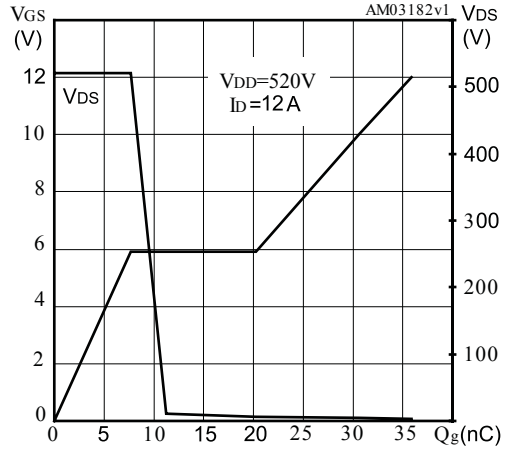


Figure 10. Normalized on resistance vs temperature

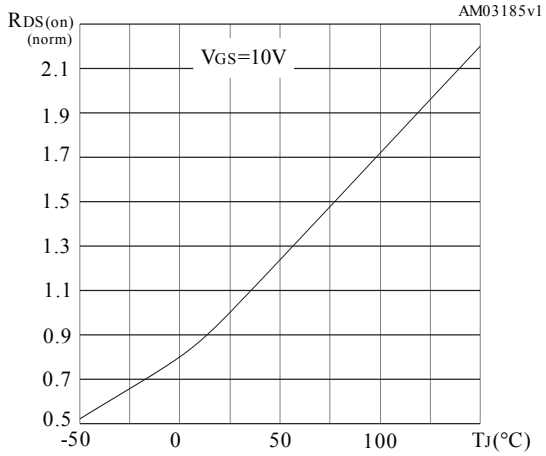


Figure 11. Normalized gate threshold voltage vs temperature

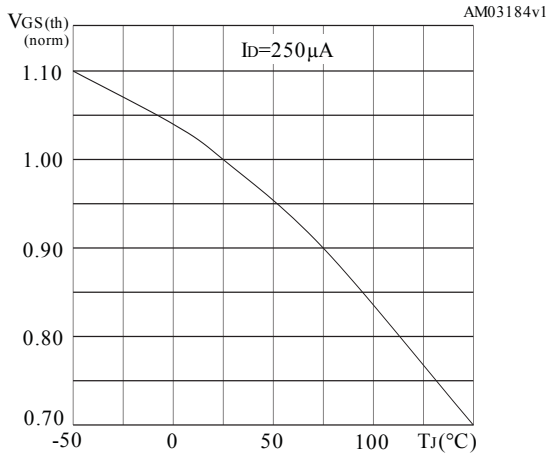


Figure 12. Source-drain diode forward characteristics

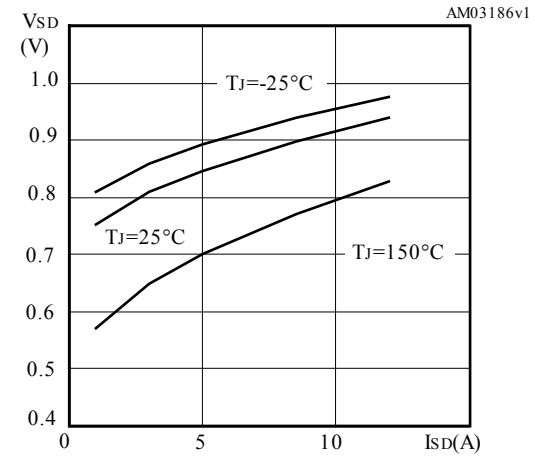
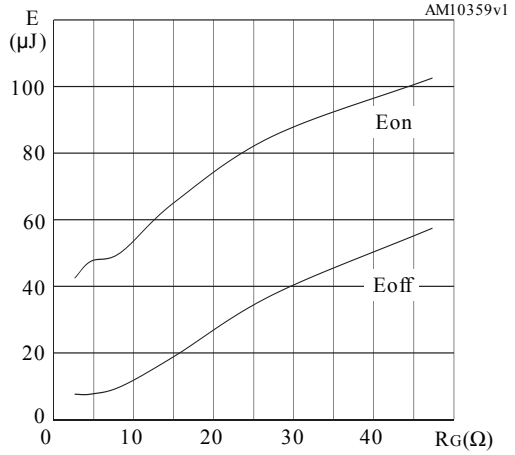


Figure 13. Switching energy vs gate resistance



Eon including reverse recovery of a SiC diode.

3 Test circuits

Figure 14. Test circuit for resistive load switching times

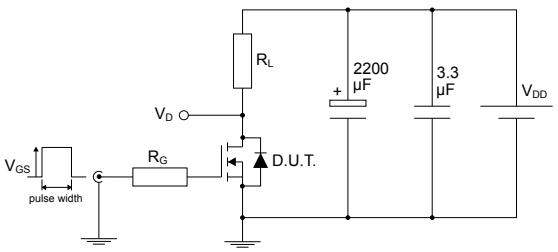


Figure 15. Test circuit for gate charge behavior

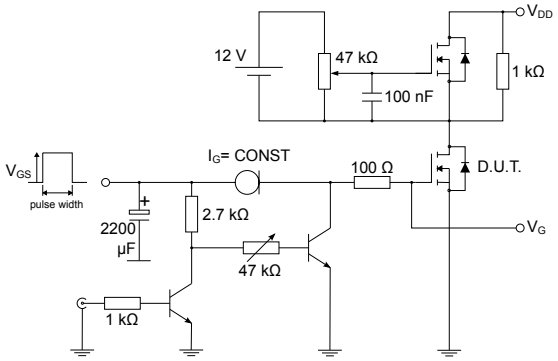


Figure 16. Test circuit for inductive load switching and diode recovery times

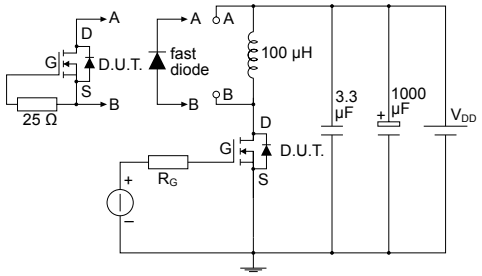


Figure 17. Unclamped inductive load test circuit

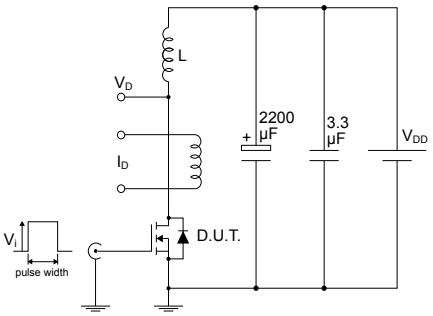


Figure 18. Unclamped inductive waveform

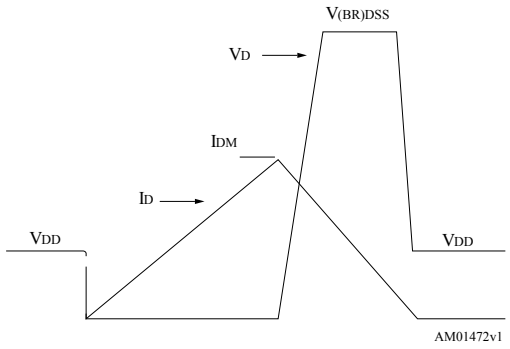
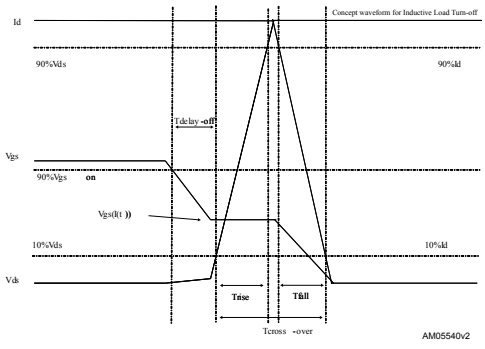


Figure 19. Switching time waveform



4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

4.1 DPAK (TO-252) type A2 package information

Figure 20. **DPAK (TO-252) type A2 package outline**

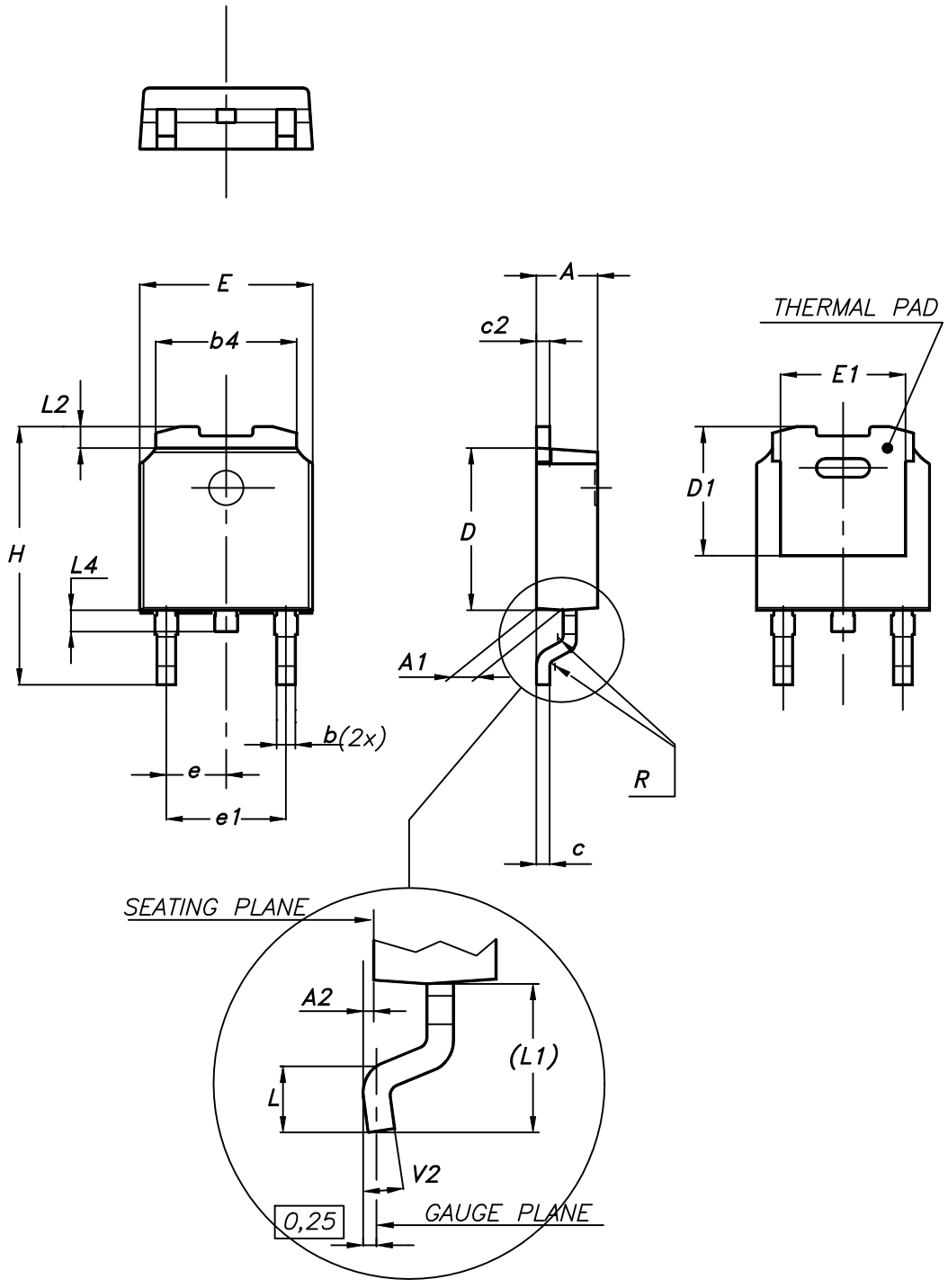
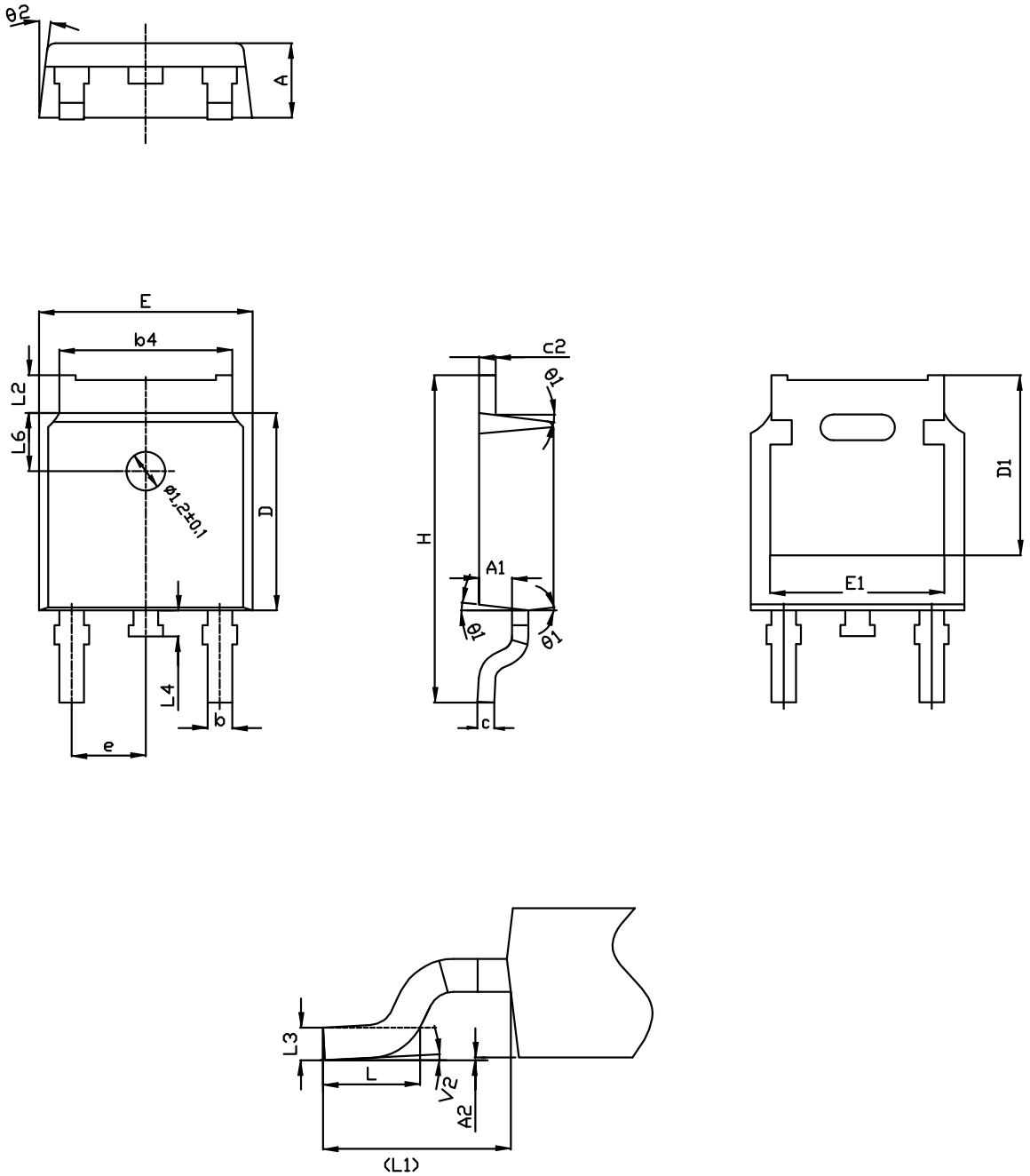


Table 8. **DPAK (TO-252) type A2 mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	2.20		2.40
A1	0.90		1.10
A2	0.03		0.23
b	0.64		0.90
b4	5.20		5.40
c	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
D1	4.95	5.10	5.25
E	6.40		6.60
E1	5.10	5.20	5.30
e	2.159	2.286	2.413
e1	4.445	4.572	4.699
H	9.35		10.10
L	1.00		1.50
L1	2.60	2.80	3.00
L2	0.65	0.80	0.95
L4	0.60		1.00
R		0.20	
V2	0°		8°

4.2 DPAK (TO-252) type C2 package information

Figure 21. **DPAK (TO-252) type C2 package outline**

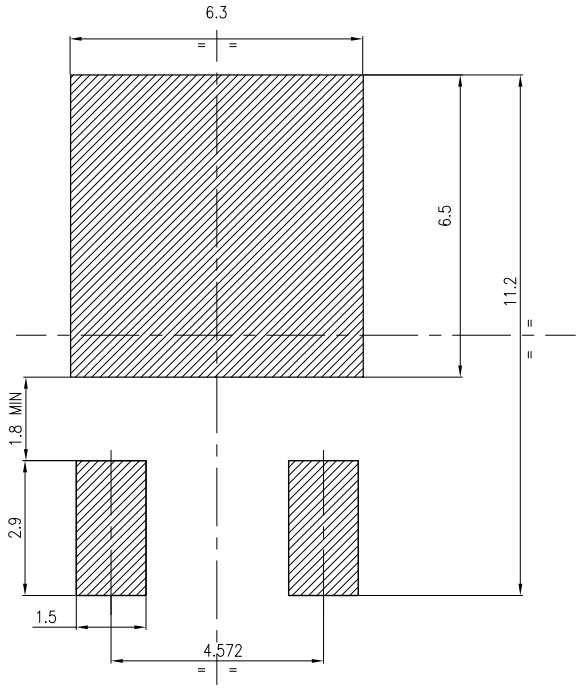


0068772_C2_25

Table 9. **DPAK (TO-252) type C2 mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	2.20	2.30	2.38
A1	0.90	1.01	1.10
A2	0.00		0.10
b	0.72		0.85
b4	5.13	5.33	5.46
c	0.47		0.60
c2	0.47		0.60
D	6.00	6.10	6.20
D1	5.10		5.60
E	6.50	6.60	6.70
E1	5.20		5.50
e	2.186	2.286	2.386
H	9.80	10.10	10.40
L	1.40	1.50	1.70
L1		2.90 REF	
L2	0.90		1.25
L3		0.51 BSC	
L4	0.60	0.80	1.00
L6		1.80 BSC	
θ1	5°	7°	9°
θ2	5°	7°	9°
V2	0°		8°

Figure 22. **DPAK (TO-252) recommended footprint (dimensions are in mm)**



4.3 DPAK (TO-252) packing information

Figure 23. **DPAK (TO-252) tape outline**

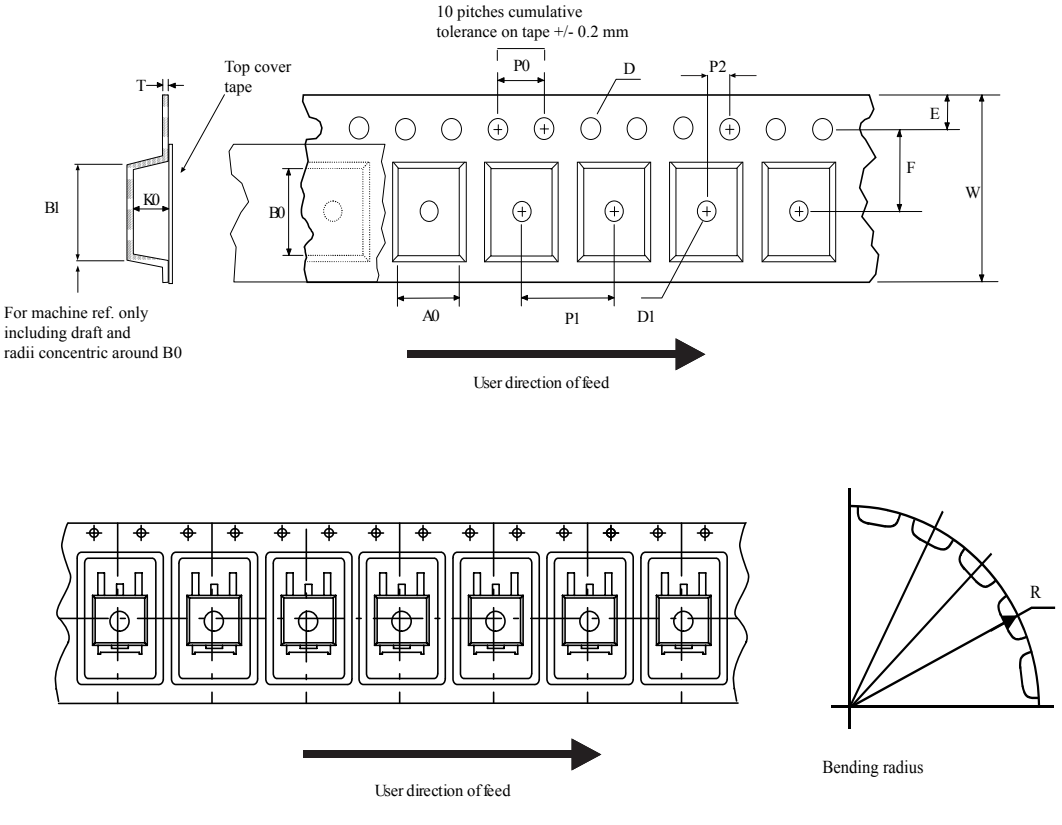
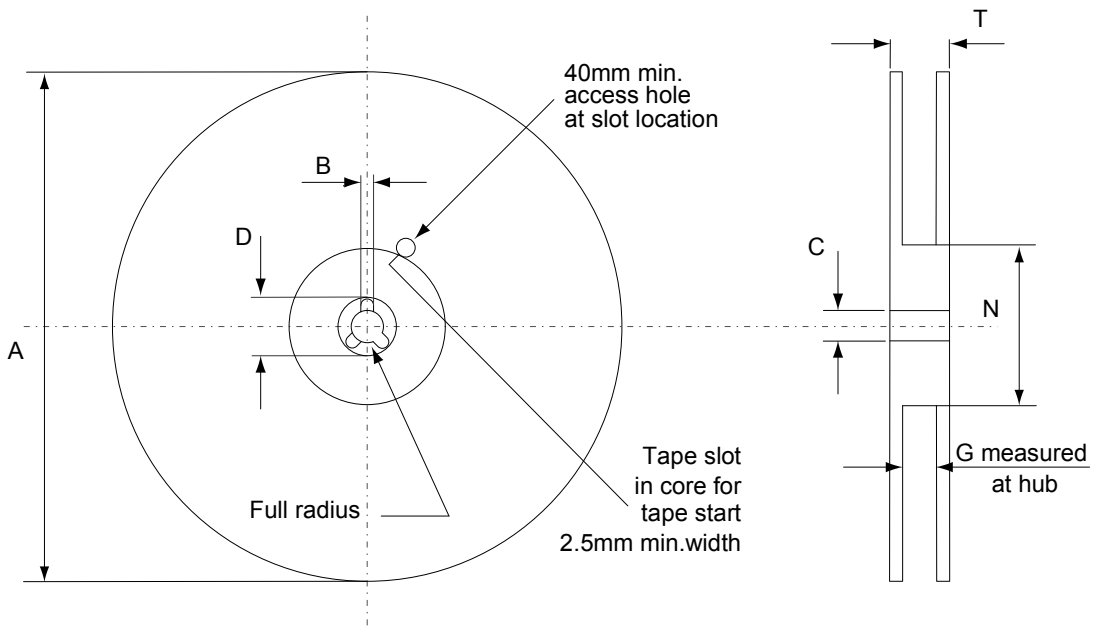


Figure 24. **DPAK (TO-252) reel outline**



AM06038v1

Table 10. **DPAK (TO-252) tape and reel mechanical data**

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	6.8	7	A		330
B0	10.4	10.6	B	1.5	
B1		12.1	C	12.8	13.2
D	1.5	1.6	D	20.2	
D1	1.5		G	16.4	18.4
E	1.65	1.85	N	50	
F	7.4	7.6	T		22.4
K0	2.55	2.75			
P0	3.9	4.1	Base qty.		2500
P1	7.9	8.1	Bulk qty.		2500
P2	1.9	2.1			
R	40				
T	0.25	0.35			
W	15.7	16.3			

Revision history

Table 11. **Document revision history**

Date	Version	Changes
09-Nov-2010	1	First release.
14-Oct-2011	2	Modified *Section 2.1: Electrical characteristics (curves)*: – *Figure 6, Figure 7, Figure 8, Figure 9, Figure 13* and *Figure 14* – Added *Figure 15* Updated $R_{DS(on)}$ value in coverpage and in *Table 4* Updated values in *Table 6* Updated Section 4: Package mechanical data and *Section 5: Packaging mechanical data*. Minor text changes.
20-Nov-2018	3	Removed maturity status indication from cover page. The document status is production data. The part number STB16N65M5 has been moved to a separate datasheet. Updated Section 4 Package information. Minor text changes.

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